

**Search Notes**

Application/Control No.

10/766,035

Examiner

Jeffrey D. Lane

Applicant(s)/Patent under  
Reexamination

ANDO ET AL.

Art Unit

2828

**SEARCHED**

Class	Subclass	Date	Examiner
372	45.01	5/22/2006	JL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
index of refraction in semiconductor laser	5/22/2006	JL